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Editorial
V.D. Agrawal **575**

Test Technology Newsletter **577**

MEMORY TESTING

Effect of Sizing and Scaling on Power Dissipation and Resilience of an RHBD SRAM Circuit
N. Pannu · N.R. Prakash · J. Kaur **579**

TEST PROGRAMMING

Development of a Simplified Programming Kit Based 16LF18856 for Embedded Systems Testing and Education in Developing Countries
J.d.D. Nguimfack-Ndongmo · K. Kentsa Zana · D.A. Asoh · N.A. Kengnou Telem · R. Kuate-Fochie · G. Kenné **589**

SCAN DESIGN FOR TESTABILITY

A Complete Design-for-Test Scheme for Reconfigurable Scan Networks
N. Lylina · C.-H. Wang · H.-J. Wunderlich **603**

SOFTWARE TEST AND VERIFICATION

Smell Detection Agent Optimization Approach to Path Generation in Automated Software Testing
S.S.V. Chandra · S.S. Sankar · H.S. Anand **623**

ANALOG AND RF CIRCUIT TESTING

A Polynomial Transform Method for Hardware Systematic Error Identification and Correction in Semiconductor Multi-Site Testing
P.O. Farayola · I. Bruce · S.K. Chaganti · A. Sheikh · S. Ravi · D. Chen **637**

HARDWARE SECURITY

Design and Evaluation of XOR Arbiter Physical Unclonable Function and its Implementation on FPGA in Hardware Security Applications
R. Naveenkumar · N.M. Sivamangai · A. Napolean · S.S.S. Priya **653**

A CatBoost Based Approach to Detect Label Flipping Poisoning Attack in Hardware Trojan Detection Systems
R. Sharma · G.K. Sharma · M. Pattanaik **667**

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